S	36	96	arc	:h	N	ot	es	•	

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/647,205	TANAKA ET AL.	
Examiner	Art Unit	
John L. Goodrow	1756	

SEARCHED					
Class	Subclass	Date	Examiner		
430	58.7	8/5/2005	JG		
	58.05				
	58.35				
	58.15				
	58.5				
	58.6				
		ų			

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
430	58.7,.8,6					
	58.05,.15					
	58.35					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
inventor name search and east	8/5/2005	JG			
•					
•					